Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	2	("5905557").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/03 15:56
L3	2	("6624866").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/03 12:39
L4	2	("20020163610").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/03 12:53
L5	389	"349"/$.ccls. and phase same range same (nm nanometer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 14:19
L6	171	L5 and (bump column spacer) and ("mu.m" ".mu.m" micrometer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:56
L7	66	L6 and (concave "contact hole" hole)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:57
L8	128	"349"/$.ccls. and phase adj difference same range same (nm nanometer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 14:45
L10	3040654	"349"/$.ccls. ("contact hole" hole concave)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 14:49

L11	7089545	"349"/$.ccls. ("contact hole" hole concave gap opening crack break puncture slit)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 14:53
L12	517	349/141.ccls. and dielectric	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 14:50
L13	438	L12 and ("contact hole" hole concave gap opening crack break puncture slit)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 14:50
L14	282	L13 and ("mu.m" ".mu.m" micrometer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 14:51
L22	36904	"349"/$.ccls. ("contact hole" hole concave) same(3 near ("mu.m" ".mu.m" micrometer))same (depth or height) same width	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 15:01
L27	1270	"349"/$.ccls. and ("contact hole" hole concave) same("mu.m" ".mu.m" micrometer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 15:03
L28	492	"349"/$.ccls. and ("contact hole" hole concave) near8("mu.m" ".mu.m" micrometer)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 15:17
L32	58	"349"/$.ccls. and ("contact hole" hole concave) near8("mu.m" ".mu.m" micrometer) same depth and width	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 15:45

L33	20	"349"/$.ccls. and ("contact hole" hole concave) near8("mu.m" ".mu. m" micrometer) same depth and width and "Cell gap"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 15:46
L34	2	("20020163610").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/03 15:57
S1	1955	349/139.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/01 13:26
S2	2	("20040223106").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/08/03 12:34
S3	4481	349/139.ccls. and (liquid adj crystal adj on adj silicon) or LCOS	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 13:23
S6	266	349/139.ccls. and (liquid adj crystal adj on adj silicon) or LCOS same (bump spacer column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/01 13:32
S7	5	349/139.ccls. and ((liquid adj crystal adj on adj silicon) or LCOS) and (TN "twisted nematic" "reflective TN" "ECB" "elctric controlled birefringence" van "vertical aligned nematic" "inv-tn" "inverse twisted nematic")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/01 13:37
S8	6	"349"/$.ccls. and ((liquid adj crystal adj on adj silicon) or LCOS) and ("dot inversion" "frame inversion" "frame-plus-bias inversion" "frame plus bias") and (TN "twisted nematic" "reflective TN" "ECB" "elctric controlled birefringence" van "vertical aligned nematic" "inv-tn" "inverse twisted nematic")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 13:36

S15	8	((liquid adj crystal adj on adj silicon) or LCOS) and ("dot inversion" "frame inversion" "frame-plus-bias inversion" "frame plus bias") and (TN "twisted nematic" "reflective TN" "ECB" "elctric controlled birefringence" van "vertical aligned nematic" "inv-tn" "inverse twisted nematic")	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 13:44
S17	10970	"349"/$.ccls.and(spacer or column or bump)sameelectrode same electric adj field	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 16:43
S19	517	349/141.ccls. and dielectric	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 17:47
S20	249	349/141.ccls. and dielectric and (bump spacer column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 18:06
S22	694	"349"/$.ccls. and insulating near8 (bump spacer column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 18:06
S23	25	"349"/141.ccls. and insulating near8 (bump spacer column)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/02 18:06